



ON Semiconductor®

FDS3512 80V N-Channel PowerTrench[®] MOSFET

General Description

This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers.

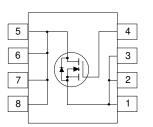
These MOSFETs feature faster switching and lower gate charge than other MOSFETs with comparable $R_{\text{DS}(\text{ON})}$ specifications.

The result is a MOSFET that is easy and safer to drive (even at very high frequencies), and DC/DC power supply designs with higher overall efficiency.

Features

- 4.0 A, 80 V $R_{DS(ON)} = 70 \text{ m}\Omega @ V_{GS} = 10 \text{ V}$ $R_{DS(ON)} = 80 \text{ m}\Omega @ V_{GS} = 6 \text{ V}$
- Low gate charge (13nC Typical)
- Fast switching speed
- High performance trench technology for extremely low $R_{\text{DS}(\text{ON})}$
- High power and current handling capability





Absolute Maximum Ratings T_{A=25°C} unless otherwise noted

Symbol	Parameter		Ratings	Units	
V _{DSS}	Drain-Source Voltage		80	V	
V _{GSS}	Gate-Source Voltage		±20	V	
I _D	Drain Current – Continuous	(Note 1a)	4.0	A	
	- Pulsed		30		
P _D	Power Dissipation for Single Operation	(Note 1a)	2.5	W	
		(Note 1b)	1.2		
		(Note 1c)	1.0		
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +175	°C	

merma			
$R_{ ext{ heta}JA}$	Thermal Resistance, Junction-to-Ambient (Note 1a)	50	°C/W
$R_{ ext{ heta}JC}$	Thermal Resistance, Junction-to-Case (Note 1)	25	°C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDS3512	FDS3512	13"	12mm	2500 units

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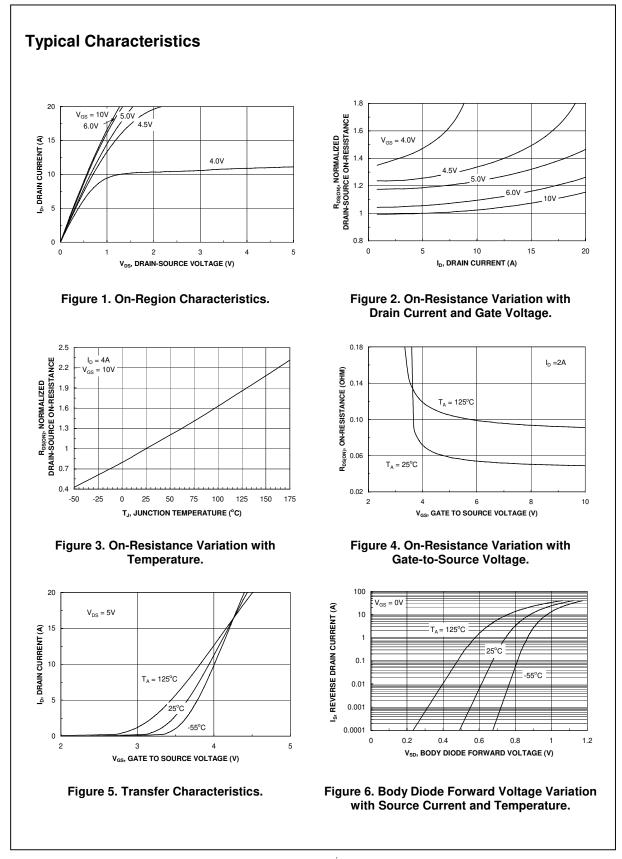
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FDS3512

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-So	ource Avalanche Ratings (Not	e 2)				
W _{DSS}	Single Pulse Drain-Source	$V_{DD} = 40 \text{ V}, I_D = 4.0 \text{ A}$			90	mJ
I _{AB}	Avalanche Energy Maximum Drain-Source				4.0	А
	Avalanche Current				1.0	~
Off Char	acteristics					
BV _{DSS}	Drain–Source Breakdown Voltage	$V_{GS}=0~V, ~~I_{D}=250~\mu A$	80			V
	Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu A$, Referenced to 25°C		80		mV/°C
ΔT_J I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 64 \text{ V}, V_{GS} = 0 \text{ V}$			1	μA
GSSF	Gate-Body Leakage, Forward	$V_{\rm GS} = 20 \text{ V}, V_{\rm DS} = 0 \text{ V}$			100	nA
GSSR	Gate-Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
			I	I		I
	Cacteristics (Note 2) Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 250 \ \mu A$	2	2.4	4	V
V _{GS(th)n}	-		2	2.4 6	4	
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D = 250 \ \mu A$, Referenced to 25°C		-0		mV/°C
R _{DS(on)}	Static Drain-Source	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 4.0 \text{ A}$		50	70	mΩ
	On-Resistance	$V_{GS} = 6 V$, $I_D = 3.7A$		55 91	80	
D(on)	On–State Drain Current		20	91	135	A
G _{FS}	Forward Transconductance	$V_{GS} = 10 \text{ V}, I_D = 4.0 \text{ A}$		14		S
						_
Dynamic C _{iss}	Characteristics	$V_{DS} = 40 V$, $V_{GS} = 0 V$,		634	r	pF
C _{oss}	Output Capacitance	f = 1.0 MHz		58		pr pF
	Reverse Transfer Capacitance			28		pr
				20		р
	ng Characteristics (Note 2)		1	7	44	
l _{d(on)}	Turn–On Delay Time Turn–On Rise Time	$V_{DD} = 40 \text{ V}, I_D = 1 \text{ A}, \\ V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$		7	14	ns
t _r				3 24	6	ns
d(off)	Turn–Off Delay Time Turn–Off Fall Time			24 4	38 8	ns
	Total Gate Charge	$V_{DS} = 40 \text{ V}, \text{ I}_{D} = 4.0 \text{ A},$		4 13	0 18	ns
Q _g	•	$V_{DS} = 40 V$, $T_D = 4.0 A$, $V_{GS} = 10 V$		2.4	10	nC
Q _{gs}	Gate-Source Charge Gate-Drain Charge			2.4		nC nC
Q _{gd}	, j	1		2.0	[
-	ource Diode Characteristics			1	0.1	•
l _s	Maximum Continuous Drain–Sourc			0.0	2.1	A V
V _{SD}	Drain–Source Diode Forward Voltage	$V_{GS} = 0 V, I_S = 2.1 A$ (Note 2)		0.8	1.2	v
otes: . R _{eJA} is the su the drain pins	m of the junction-to-case and case-to-ambient the R $_{\rm eJC}$ is guaranteed by design while R $_{\rm eCA}$ is det $_{\rm e}$	ermal resistance where the case thermal reference ermined by the user's board design.		s the solde	ər mounting	surface of

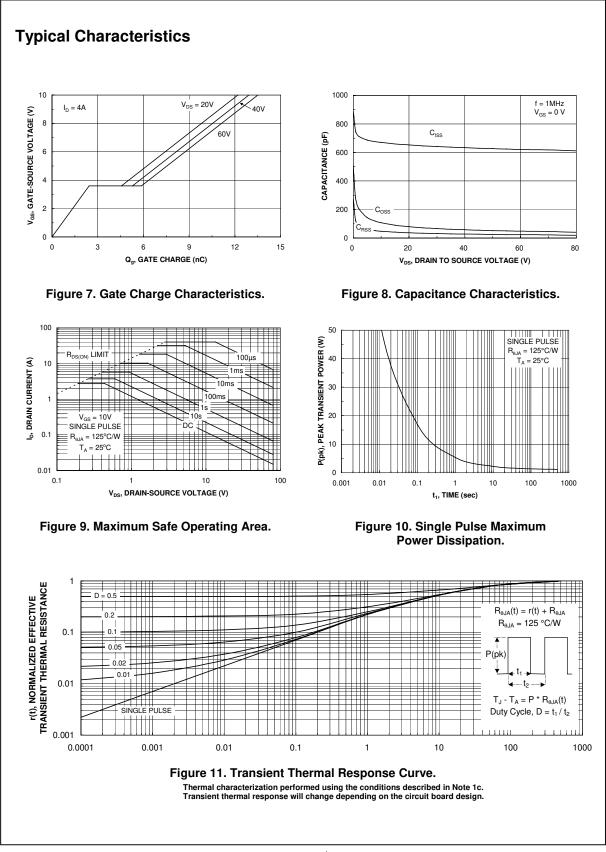
2. Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0%

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